Notification about the transfer of the semiconductor business

The semiconductor business of Panasonic Corporation was transferred on September 1, 2020 to Nuvoton Technology Corporation (hereinafter referred to as "Nuvoton"). Accordingly, Panasonic Semiconductor Solutions Co., Ltd. became under the umbrella of the Nuvoton Group, with the new name of Nuvoton Technology Corporation Japan (hereinafter referred to as "NTCJ").

In accordance with this transfer, semiconductor products will be handled as NTCJ-made products after September 1, 2020. However, such products will be continuously sold through Panasonic Corporation.

Publisher of this Document is NTCJ.

If you would find description "Panasonic" or "Panasonic semiconductor solutions", please replace it with NTCJ.

* Except below description page

"Request for your special attention and precautions in using the technical information and semiconductors described in this book"

Nuvoton Technology Corporation Japan



MOS FET FK8V03020L

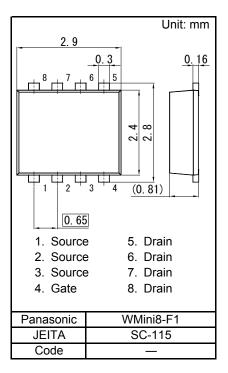
FK8V03020L Silicon N-channel MOS FET

For lithium-ion secondary battery protecion circuit

Features

- Low drain-source On-state Resistance RDS(on) typ = 5.4 m Ω (VGS = 4.5 V)
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL:Level 1 compliant)
- Marking Symbol: 3B

Packaging Embossed type (Thermo-compression sealing): 3 000 pcs / reel (standard)



Internal Connection (D) (Ś) (\$) (\overline{G}) Pin Name 1. Source 5. Drain 6. Drain 2. Source 3. Source 7. Drain 4. Gate 8. Drain Figure1 FR4 Glass-Epoxy Board 25.4 mm × 25.4 mm × 0.8 mm

■ Absolute Maximum Ratings Ta = 25 °C

	0				
Parameter	Symbol	Rating	Unit		
Drain-source Voltage	VDS	33	V		
Gate-source Voltage	VGS	±20	V		
Drain Current (Steady State) ^{*1}	ID	14			
Drain Current (t = 10 s) ^{*1}		18			
Drain Current (Pulsed) *1,*2	IDp	56	А		
Source Current (Pulsed)	ISp	14			
(Body Diode) ^{*1,*2}	(BD)	14			
Total Power Dissipation (Steady State) *1	PD	1	W		
Total Power Dissipation (t = 10 s) ^{*1}	FD	1.6	vv		
Channel Temperature	Tch	150	°C		
Operating Ambient Temperature	Topr	-40 to +85	°C		
Storage Temperature Range	Tstg	-55 to +150	°C		
Avalanche Current *3	lar	60	А		
Nate: *1. Device recursted on a place energy beard (Cap Figure 1)					

Note: *1 Device mounted on a glass-epoxy board (See Figure 1)

*2 Pulse test: Ensure that the channel temperature does not exceed 150°C

*3 Conditions: VDS = 24 V, VGS = 10 V, L = 10 μH

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MOS FET FK8V03020L

■ Electrical Characteristics Ta = 25°C ± 3°C

Static	Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, $VGS = 0 V$	33			V
Zero Gate Voltage Drain Current	IDSS	VDS = 33 V, VGS = 0 V			1	μA
Gate-source Leakage Current	IGSS	$VGS = \pm 16 V, VDS = 0 V$			±10	μA
Gate-source Threshold Voltage	Vth	ID = 2.2 mA, VDS = 10 V	1.0		3.0	V
Drain-source On-state Resistance *1	RDS(on)1	ID = 7A, VGS = 10 V		3.6	4.6	mΩ
	RDS(on)2	ID = 7A, VGS = 4.5 V		5.4	9.8	

Dynamic Characteristics

Input Capacitance	Ciss		1500	
Output Capacitance	Coss	VDS = 10 V, VGS = 0 V f = 1 MHz	300	pF
Reverse Transfer Capacitance	Crss		200	
Turn-on Delay Time *2	td(on)	VDD = 15 V, VGS = 0 to 10 V	10	
Rise Time ^{*2}	tr	ID = 7 A	5	ns
Turn-off Delay Time ^{*2}	td(off)	VDD = 15 V, VGS = 10 to 0 V	200	115
Fall Time ^{*2}	tf	ID = 7 A	150	
Total Gate Charge	Qg	VDD = 15 V, VGS = 0 to 4.5 V,	14	
Gate-source Charge	Qgs	ID = 14 A	4	nC
Gate-drain Charge	Qgd		6	

Body Diode Characteristic

Diode Forward Voltage ^{*1}	VSD	IS = 7 A, VGS = 0 V	0.8	1.2	V	
Note: 1 Measuring methods are based on IAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors						

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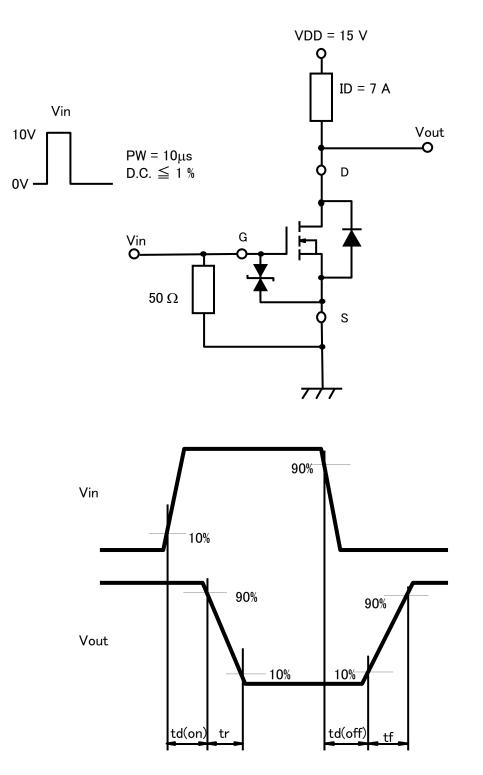
2. *1 Pulse test: Ensure that the channel temperature does not exceed 150°C

*2 Measurement circuit for Turn-on Delay Time/Rise Time/Turn-off Delay Time/Fall Time

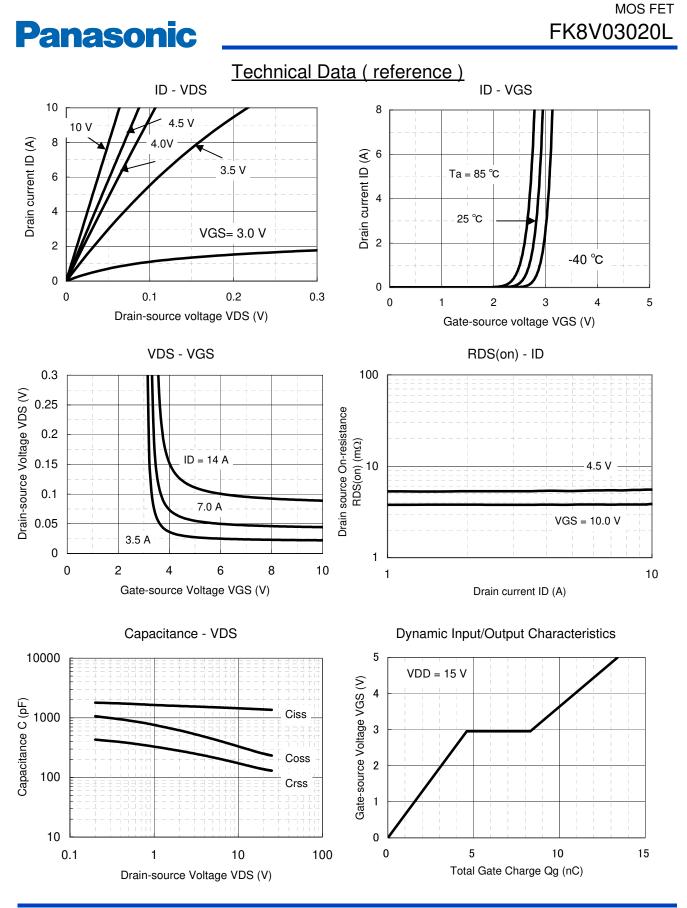
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*2 Measurement circuit for Turn-on Delay Time/Rise Time/Turn-off Delay Time/Fall Time

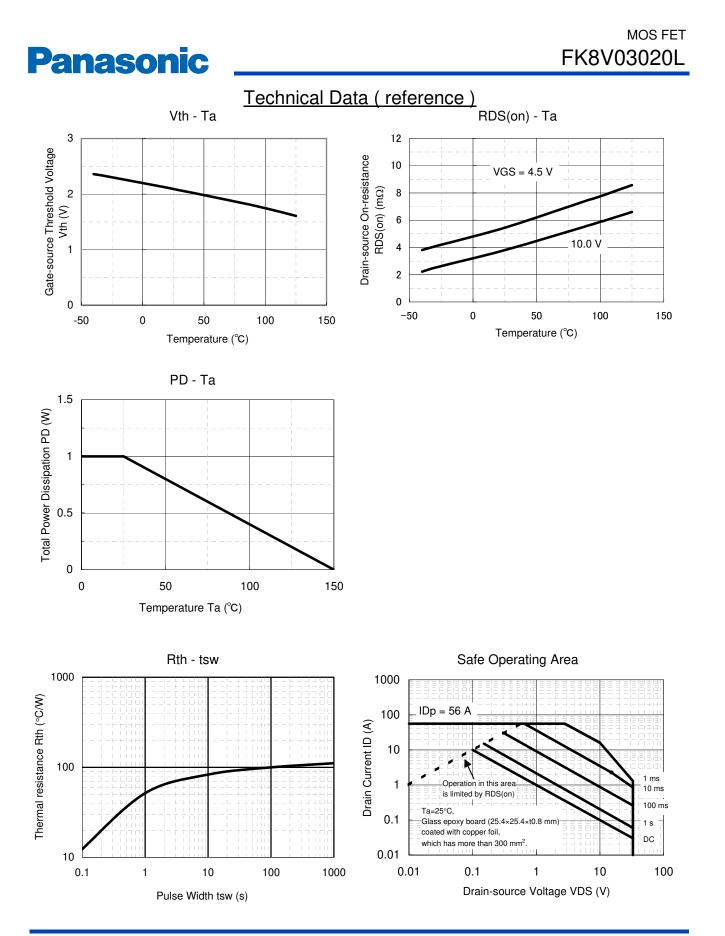


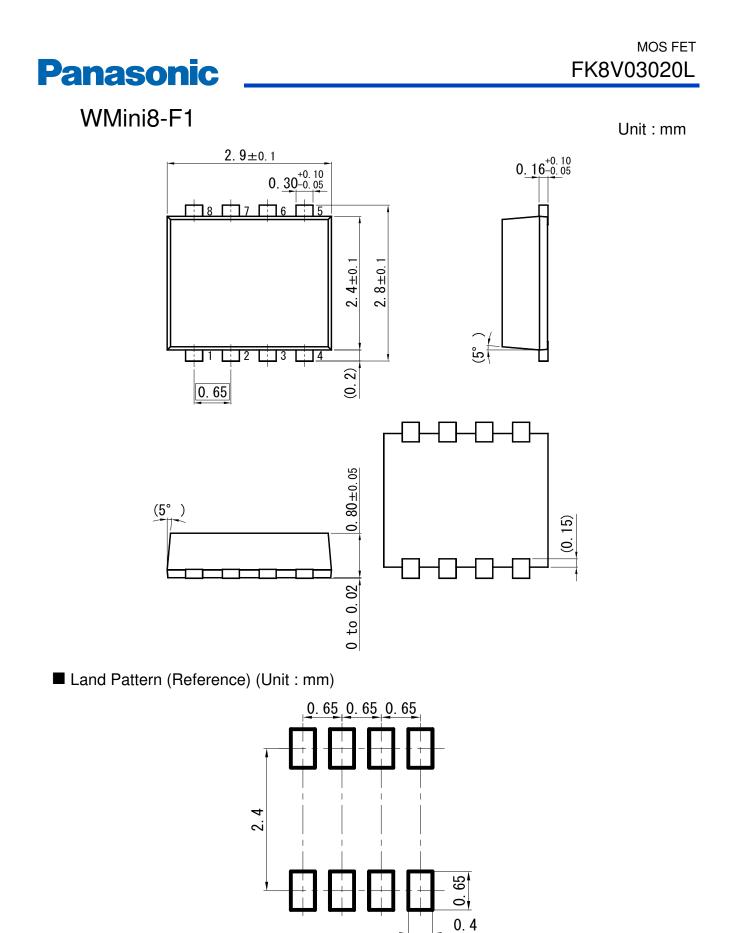
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